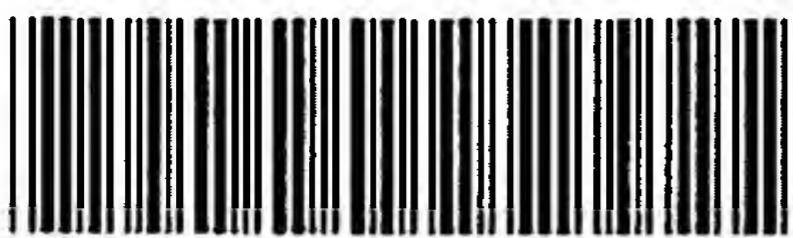


Index of Claims

Application/Control No.
10/047,717
Examiner
Tan Dean D. Nguyen
**Applicant(s)/Patent under
Reexamination**
KNAPP, RICHARD J.
Art Unit
3629

✓	Rejected
=	Allowed

-	(Through numeral) Cancelled
÷	Restricted

N	Non-Elected
I	Interference

A	Appeal
O	Objected

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